

Form PTO 1449  U.S. Department of Commerce Patent and Trademark Office  Information Disclosure Statement by Applicant	ATTY. DOCKET NUMBER <b>HITA.0419</b>	SERIAL NUMBER <b>To be assigned</b>
	APPLICANT <b>Mizuno</b>	
	FILING DATE <b>Concurrently herewith</b>	GROUP

**U.S. Patent Documents**

Examiner Initial	Cited by Examiner in Parent	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASSES	FILING DATE
JZ	X	6,107,700	8/22/2000	Ishikawa et al	—	—	11/13/98
JZ	X	5,724,297	3/3/98	Noda et al.	—	—	12/12/96
JZ	X	5,614,847	3/25/97	Kawahara et al.	—	—	8/24/94
JZ	X	5,606,265	2/25/97	Sakata et al	—	—	3/21/96
JZ	X	5,583,457	12/10/96	Horiguchi et al.	—	—	2/8/94

**Foreign Patent Documents**

Examiner Initial		DOCUMENT NUMBER	FILING DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
							YES	NO
JZ	AA	8-152945	11/28/94	Japan	—	—	Abstract	X

**Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)**

	AB	Shckhar Borkar, <i>Design Challenges of Technology Scaling</i> , July-August 1999 IEEE, pp. 23-29
JZ	AC	Jerry M. Soden, Charles F. Hawkins and Anthony C. Miller, <i>Identifying defects in deep-submicron CMOS lcs</i> , <i>IEEE Spectrum</i> , September 1996, pp. 66-71
JZ	AD	Takeshi Sakata, Masashi Horiguchi and Kiyoo Itoh, <i>Subthreshold-current reduction circuits for multi-gigabit dram's</i> , Central Research Laboratory, Hitachi, Ltd. , pp. 45-46
JZ	AE	Takashi Inukai and Toshiro Hiramoto, <i>Suppression of Stand-By tunnel Current in Ultra-Thin Gate Oxide MOSFETs by dual Oxide Thickness MTCMOS(DOT-MTCMOS)</i> , 1999 International Conference of Solid State Devices and Materials, Tokyo, pp.264--265
JZ	AF	Katsuhiko Seta, Hiroyuki Hara, Tadahiro Kuroda, Mazakazu Kakumu, and Takayasu Sakurai, <i>50% Active-Power Saving without Speed Degradation using Standby Power Reduction (SPR) Circuit</i> , 1995 IEEE International Solid State Circuits Conference, pp. 318-319
JZ	AG	Maurice J. Bach, <i>The Design of the Unix Operating System</i> , Prentice Hall, Inc. , 1986 by Bell Telephone Laboratories, pp. 210-263

EXAMINER <i>Jeffrey Zweizig</i>	DATE CONSIDERED <i>2/23/04</i>
EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant	